

### General Description

The ICS8430S10I-02 is a PLL-based clock generator specifically designed for Cavium Networks SoC processors. This high performance device is optimized to generate the processor core reference clock, the DDR reference clocks, the PCI/PCI-X bus clocks, and the clocks for both the Gigabit Ethernet MAC and PHY. The clock generator offers ultra low-jitter, low-skew clock outputs, and edge rates that easily meet the input requirements for the CN30XX/CN31XX/CN38XX/CN58XX processors. The output frequencies are generated from a 25MHz external input source or an external 25MHz parallel resonant crystal. The extended temperature range of the ICS8430S10I-02 supports telecommunication, networking, and storage requirements.

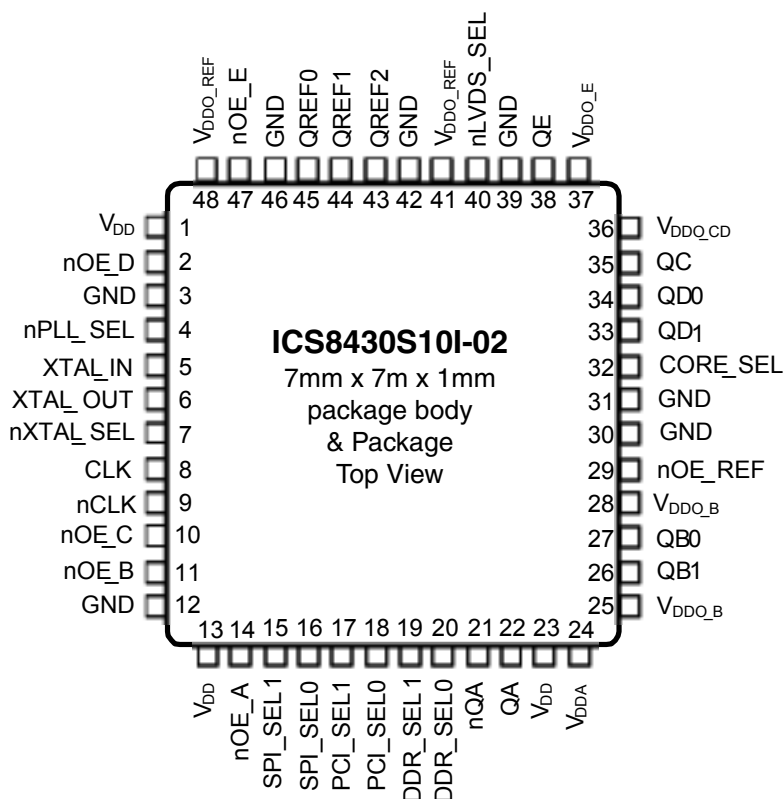
### Applications

- Systems using Cavium Processors
- CPE Gateway Design
- Home Media Servers
- 802.11n AP or Gateway
- Soho Secure Gateway
- Soho SME Gateway
- Wireless Soho and SME VPN Solutions
- Wired and Wireless Network Security
- Web Servers and Exchange Servers

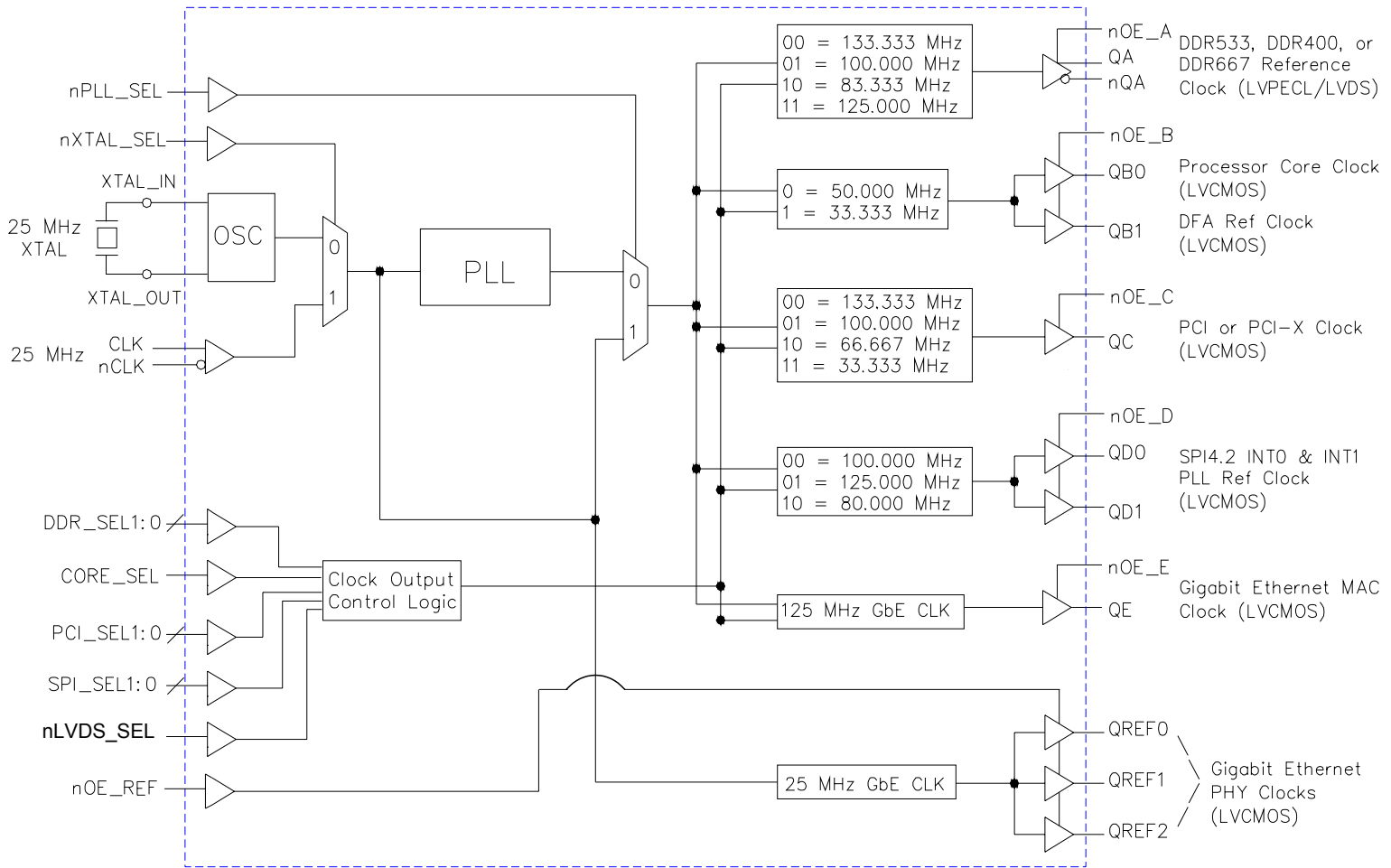
### Features

- One selectable differential output pair for DDR 533/400/667, LVPECL, LVDS interface levels
- Nine LVCMOS/ LVTTTL outputs, 20Ω typical output impedance
- Selectable external crystal or differential (single-ended) input source
- Crystal oscillator interface designed for 25MHz, parallel resonant crystal
- Differential input pair (CLK, nCLK) accepts LVPECL, LVDS, SSTL input levels
- Internal resistor bias on nCLK pin allows the user to drive CLK input with external single-ended (LVCMOS/ LVTTTL) input levels
- Power output supply modes  
LVDS and LVPECL – full 3.3V  
LVCMOS – full 3.3V or mixed 3.3V core/2.5V output
- -40°C to 85°C ambient operating temperature
- Available in lead-free (RoHS 6) package

### Pin Assignment



# Block Diagram



**Table 1. Pin Descriptions**

Number	Name	Type		Description
1, 13, 23	V <sub>DD</sub>	Power		Core supply pins.
2	nOE_D	Input	Pulldown	Active LOW output enable for Bank D outputs. When logic HIGH, the outputs are in high impedance (HI-Z). When logic LOW, the outputs are enabled. LVCMOS/LVTTL interface levels.
3, 12, 30, 31, 39, 42, 46	GND	Power		Power supply ground.
4	nPLL_SEL	Input	Pulldown	PLL bypass. When LOW, PLL is enable. When HIGH, PLL is bypassed. LVCMOS/LVTTL interface levels.
5, 6	XTAL_IN, XTAL_OUT	Input		Parallel resonant crystal interface. XTAL_OUT is the output, XTAL_IN is the input.
7	nXTAL_SEL	Input	Pulldown	Selects XTAL inputs when LOW. Selects differential clock (CLK, nCLK) input when HIGH. LVCMOS/LVTTL interface levels.
8	CLK	Input	Pulldown	Non-inverting differential clock input.
9	nCLK	Input	Pullup/ Pulldown	Inverting differential clock input. Internal resistor bias to V <sub>DD</sub> /2.
10	nOE_C	Input	Pulldown	Active LOW output enable for Bank C output. When logic HIGH, the output is in high impedance (HI-Z). When logic LOW, QC output is enabled. LVCMOS/LVTTL interface levels.
11	nOE_B	Input	Pulldown	Active LOW output enable for Bank B outputs. When logic HIGH, the outputs are in high impedance (HI-Z). When logic LOW, the outputs are enabled. LVCMOS/LVTTL interface levels.
14	nOE_A	Input	Pulldown	Active LOW output enable for Bank A outputs. LVCMOS/LVTTL interface levels.
15, 16	SPI_SEL1, SPI_SEL0	Input	Pulldown	Selects the SPI PLL clock reference frequency. See Table 3D.
17, 18	PCI_SEL1, PCI_SEL0	Input	Pulldown	Selects the PCI, PCI-X reference clock output frequency. See Table 3C. LVCMOS/LVTTL interface levels.
19, 20	DDR_SEL1, DDR_SEL0	Input	Pulldown	Selects the DDR reference clock output frequency. See Table 3B. LVCMOS/LVTTL interface levels.
21, 22	nQA, QA	Output		Differential output pair. Selectable between LVPECL and LVDS interface levels.
24	V <sub>DDA</sub>	Power		Analog supply pin.
25, 28	V <sub>DDO_B</sub>	Power		Bank B output supply pins. 3.3 V or 2.5V supply.
26, 27	QB1, QB0	Output		Single-ended Bank B outputs. LVCMOS/LVTTL interface levels.
29	nOE_REF	Input	Pulldown	Active LOW output enable. When logic HIGH, the QREF[2:0] outputs are in high impedance (HI-Z). When logic LOW, the QREF[2:0] outputs are enabled. LVCMOS/ LVTTL interface levels.
32	CORE_SEL	Input	Pulldown	Selects the processor core clock output frequency. The output frequency is 50MHz when LOW, and 33.333MHz when HIGH. See Table 3A. LVCMOS/LVTTL interface levels.
33, 34	QD1, QD0	Output		Single-end Bank D outputs. LVCMOS/LVTTL interface levels.
35	QC	Output		Single-end Bank C output. LVCMOS/LVTTL interface levels.
36	V <sub>DDO_CD</sub>	Power		Bank C and Bank D output supply pin. 3.3 V or 2.5V supply.

Pin descriptions continue on the next page.

Number	Name	Type		Description
37	V <sub>DDO_E</sub>	Power		Bank E output supply pin. 3.3 V or 2.5V supply.
38	QE	Output		Single-end Bank E output. LVCMOS/LVTTL interface levels.
40	nLVDS_SEL	Input	Pulldown	Selects between LVDS and LVPECL interface levels on differential output pair QA and nQA. When LOW, LVDS interface levels are selected. When HIGH, LVPECL is selected. See Table 3E.
41, 48	V <sub>DDO_REF</sub>	Power		Bank QREF output supply pins. 3.3 V or 2.5V supply.
43, 44, 45	QREF2, QREF1, QREF0	Output		Single-ended reference clock outputs. LVCMOS/LVTTL interface levels.
47	nOE_E	Input	Pulldown	Active LOW output enable for Bank E outputs. When logic HIGH, the outputs are in high impedance (HI-Z). When logic LOW, the outputs are enabled. LVCMOS/LVTTL interface levels.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, *Pin Characteristics*, for typical values.

**Table 2. Pin Characteristics**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C <sub>IN</sub>	Input Capacitance			2		pF
C <sub>PD</sub>	Power Dissipation Capacitance (per output)	V <sub>DD</sub> , V <sub>DDO_X</sub> = 3.465V		10		pF
		V <sub>DD</sub> = 3.465V, V <sub>DDO_X</sub> = 2.625V		5		pF
R <sub>PULLUP</sub>	Input Pullup Resistor			51		kΩ
R <sub>PULLDOWN</sub>	Input Pulldown Resistor			51		kΩ
R <sub>OUT</sub>	Output Impedance	QB[0:1], QC, QD[0:1], QE QREF[0:2]	V <sub>DDO_X</sub> = 3.465V	20		Ω
		QB[0:1], QC, QD[0:1], QE QREF[0:2]	V <sub>DDO_X</sub> = 2.625V	25		Ω

NOTE: V<sub>DDO\_X</sub> denotes V<sub>DDO\_B</sub>, V<sub>DDO\_CD</sub>, V<sub>DDO\_E</sub> and V<sub>DDO\_REF</sub>.

## Function Tables

**Table 3A. Control Input Function Table**

Input	Output Frequency
<b>CORE_SEL</b>	<b>QB[0:1]</b>
0	50MHz (default)
1	33.333MHz

**Table 3B. Control Input Function Table**

Inputs		Output Frequency
DDR_SEL1	DDR_SEL0	QA, nQA
0	0	133.333MHz (default)
0	1	100.000MHz
1	0	83.333MHz
1	1	125.000MHz

**Table 3C. Control Input Function Table**

Inputs		Output Frequency
PCI_SEL1	PCI_SEL0	QC
0	0	133.333MHz (default)
0	1	100.000MHz
1	0	66.6667MHz
1	1	33.333MHz

**Table 3D. Control Input Function Table**

Inputs		Output Frequency
SPI_SEL1	SPI_SEL0	QD[0:1]
0	0	100.000MHz (default)
0	1	125.000MHz
1	0	80.000MHz

**Table 3E. Control Input Function Table**

Input	Output Levels
<b>nLVDS_SEL</b>	<b>QA, nQA</b>
0	LVDS (default)
1	LVPECL

## Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, $V_{DD}$	4.6V
Inputs, $V_I$	-0.5V to $V_{DD} + 0.5V$
Outputs, $V_O$ (LVCMOS)	-0.5V to $V_{DD} + 0.5V$
Outputs, $I_O$ (LVDS) Continuous Current Surge Current	10mA 15mA
Outputs, $I_O$ (LVPECL) Continuous Current Surge Current	50mA 100mA
Package Thermal Impedance, $\theta_{JA}$	33.1°C/W (0 mps)
Storage Temperature, $T_{STG}$	-65°C to 150°C

## DC Electrical Characteristics

**Table 4A. LVCMOS Power Supply DC Characteristics,  $V_{DD} = V_{DDO\_X} = 3.3V \pm 5\%$ ,  $T_A = -40^\circ\text{C}$  to  $85^\circ\text{C}$**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Core Supply Voltage		3.135	3.3	3.465	V
$V_{DDA}$	Analog Supply Voltage		$V_{DD} - 0.25$	3.3	$V_{DD}$	V
$V_{DDO\_X}$	Output Supply Voltage		3.135	3.3	3.465	V
$I_{DD}$	Power Supply Current				180	mA
$I_{DDA}$	Analog Supply Current				25	mA
$I_{DDO\_X}$	Output Supply Current	No Load, CLK selected			60	mA

NOTE:  $V_{DDO\_X}$  denotes  $V_{DDO\_B}$ ,  $V_{DDO\_CD}$  and  $V_{DDO\_REF}$ .

**Table 4B. LVCMOS Power Supply DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{DDO\_X} = 2.5V \pm 5\%$ ,  $T_A = -40^\circ\text{C}$  to  $85^\circ\text{C}$**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Core Supply Voltage		3.135	3.3	3.465	V
$V_{DDA}$	Analog Supply Voltage		$V_{DD} - 0.25$	3.3	$V_{DD}$	V
$V_{DDO\_X}$	Output Supply Voltage		2.375	2.5	2.625	V
$I_{DD}$	Power Supply Current				102	mA
$I_{DDA}$	Analog Supply Current				25	mA
$I_{DDO\_X}$	Output Supply Current	No Load, CLK selected			42	mA

NOTE:  $V_{DDO\_X}$  denotes  $V_{DDO\_B}$ ,  $V_{DDO\_CD}$  and  $V_{DDO\_REF}$ .

**Table 4C. LVPECL Power Supply DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{EE} = 0V$ ,  $T_A = -40^\circ C$  to  $85^\circ C$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Core Supply Voltage		3.135	3.3	3.465	V
$V_{DDA}$	Analog Supply Voltage		$V_{DD} - 0.25$	3.3	$V_{DD}$	V
$I_{EE}$	Power Supply Current	nLVDS_SEL = 1			180	mA
$I_{DDA}$	Analog Supply Current				25	mA

**Table 4D. LVDS Power Supply DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $T_A = -40^\circ C$  to  $85^\circ C$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Core Supply Voltage		3.135	3.3	3.465	V
$V_{DDA}$	Analog Supply Voltage		$V_{DD} - 0.25$	3.3	$V_{DD}$	V
$I_{DD}$	Power Supply Current	nLVDS_SEL = 0			192	mA
$I_{DDA}$	Analog Supply Current				25	mA

**Table 4E. LVCMOS/LVTTL DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{DDO\_X} = 3.3V \pm 5\%$  or  $2.5V \pm 5\%$ ,  $T_A = -40^\circ C$  to  $85^\circ C$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{IH}$	Input High Voltage		2.2		$V_{DD} + 0.3$	V
$V_{IL}$	Input Low Voltage		-0.3		0.8	V
$I_{IH}$	Input High Current	DDR_SEL[0:1], nPLL_SEL, nLVDS_SEL, PCI_SEL[0:1], nOE_REF, SPI_SEL[0:1], nOE_[A:E], nXTAL_SEL, CORE_SEL  $V_{DD} = V_{IN} = 3.465V$			150	$\mu A$
$I_{IL}$	Input Low Current	DDR_SEL[0:1], nPLL_SEL, nLVDS_SEL, PCI_SEL[0:1], nOE_REF, SPI_SEL[0:1], nOE_[A:E], nXTAL_SEL, CORE_SEL  $V_{DD} = 3.465V, V_{IN} = 0V$	-10			$\mu A$
$V_{OH}$	Output High Voltage	$V_{DDO\_X} = 3.465V,$ $I_{OH} = -12mA$	2.6			V
		$V_{DDO\_X} = 2.625V,$ $I_{OH} = -12mA$	1.8			V
$V_{OL}$	Output Low Voltage	$V_{DDO\_X} = 3.465V,$ $I_{OL} = 12mA$			0.65	V
		$V_{DDO\_X} = 2.625V,$ $I_{OL} = 12mA$			0.55	V

NOTE:  $V_{DDO\_X}$  denotes  $V_{DDO\_B}$ ,  $V_{DDO\_CD}$ ,  $V_{DDO\_E}$  and  $V_{DDO\_REF}$ .

**Table 4F. Differential DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $T_A = -40^\circ\text{C}$  to  $85^\circ\text{C}$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$I_{IH}$	Input High Current	CLK, nCLK $V_{DD} = V_{IN} = 3.465V$			150	$\mu\text{A}$
$I_{IL}$	Input Low Current	CLK $V_{DD} = 3.465V, V_{IN} = 0V$	-10			$\mu\text{A}$
		nCLK $V_{DD} = 3.465V, V_{IN} = 0V$	-150			$\mu\text{A}$
$V_{PP}$	Peak-to-Peak Input Voltage; NOTE 1		0.15		1.3	V
$V_{CMR}$	Common Mode Input Voltage; NOTE 1, 2		1.2		$V_{DD}$	V

NOTE 1:  $V_{IL}$  should not be less than -0.3V.NOTE 2. Common mode voltage is defined as  $V_{IH}$ .**Table 4G. LVPECL DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{EE} = 0V$ ,  $T_A = -40^\circ\text{C}$  to  $85^\circ\text{C}$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{OH}$	Output High Voltage; NOTE 1		$V_{DD} - 1.4$		$V_{DD} - 0.9$	V
$V_{OL}$	Output Low Voltage; NOTE 1		$V_{DD} - 2.0$		$V_{DD} - 1.7$	V
$V_{SWING}$	Peak-to-Peak Output Voltage Swing		0.55		1.0	V

NOTE 1: Outputs terminated with  $50\Omega$  to  $V_{DD} - 2V$ .**Table 4H. LVDS DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $T_A = -40^\circ\text{C}$  to  $85^\circ\text{C}$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{OD}$	Differential Output Voltage		300	500	600	mV
$\Delta V_{OD}$	$V_{OD}$ Magnitude Change				50	mV
$V_{OS}$	Offset Voltage		1.04	1.14	1.24	V
$\Delta V_{OS}$	$V_{OS}$ Magnitude Change				50	mV

**Table 5. Crystal Characteristics**

Parameter	Test Conditions	Minimum	Typical	Maximum	Units
Mode of Oscillation		Fundamental			
Frequency			25		MHz
Equivalent Series Resistance (ESR)				50	$\Omega$
Shunt Capacitance				7	pF

NOTE: Characterized using an 18pF parallel resonant crystal.

## AC Electrical Characteristics

**Table 6. AC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{DDO\_X} = 3.3V \pm 5\%$  or  $2.5V \pm 5\%$ ,  $T_A = -40^\circ\text{C}$  to  $85^\circ\text{C}$**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$f_{OUT}$	Output Frequency	QA, nQA	DDR_SEL[1:0] = 00		133.333	MHz
		QA, nQA	DDR_SEL[1:0] = 01		100	MHz
		QA, nQA	DDR_SEL[1:0] = 10		83.333	MHz
		QA, nQA	DDR_SEL[1:0] = 11		125	MHz
		QBx	CORE_SEL = 0		50	MHz
		QBx	CORE_SEL = 1		33.333	MHz
		QC	PCI_SEL[1:0] = 00		133.333	MHz
		QC	PCI_SEL[1:0] = 01		100	MHz
		QC	PCI_SEL[1:0] = 10		66.667	MHz
		QC	PCI_SEL[1:0] = 11		33.333	MHz
		QDx	SPI_SEL[1:0] = 00		100	MHz
		QDx	SPI_SEL[1:0] = 01		125	MHz
		QDx	SPI_SEL[1:0] = 10		80	MHz
		QE			125	MHz
QREFx			25	MHz		
$t_{sk}(b)$	Bank Skew; NOTE 2, 4	QREFx			30	ps
$t_{sk}(pp)$	Part-to-Part Skew; NOTE 3, 4	QREFx			200	ps
$t_{jit}(cc)$	Cycle-to-Cycle Jitter	QA, nQA	measured at crosspoint		60	ps
		QBx, QC, QDx			115	ps
		QE			120	ps
$t_{jit}(per)$	RMS Period Jitter	QA, nQA	measured at crosspoint		40	ps
$t_{jit}(hper)$	RMS Half-period Jitter	QA, nQA	measured at crosspoint		50	ps
$t_{jit}(\emptyset)$	RMS Phase Jitter, (Random); NOTE 1	QREFx	25MHz (10kHz to 5MHz)		0.58	ps
		QE	125MHz (1.875MHz to 20MHz)		0.72	ps
$t_R / t_F$	Output Rise/Fall Time	QA, nQA	20% to 80%	100	300	ps
		QBx, QC, QDx, QE, QREFx		400	1200	ps
odc	Output Duty Cycle	QA, nQA		48	52	%
		QBx, QC, QDx, QE, QREFx		40	60	%
$t_{LOCK}$	Lock Time				100	ms

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE: All parameters measured at maximum  $f_{OUT}$  unless noted otherwise.

NOTE:  $V_{DDO\_X}$  denotes  $V_{DDO\_B}$ ,  $V_{DDO\_CD}$ ,  $V_{DDO\_E}$  and  $V_{DDO\_REF}$ .

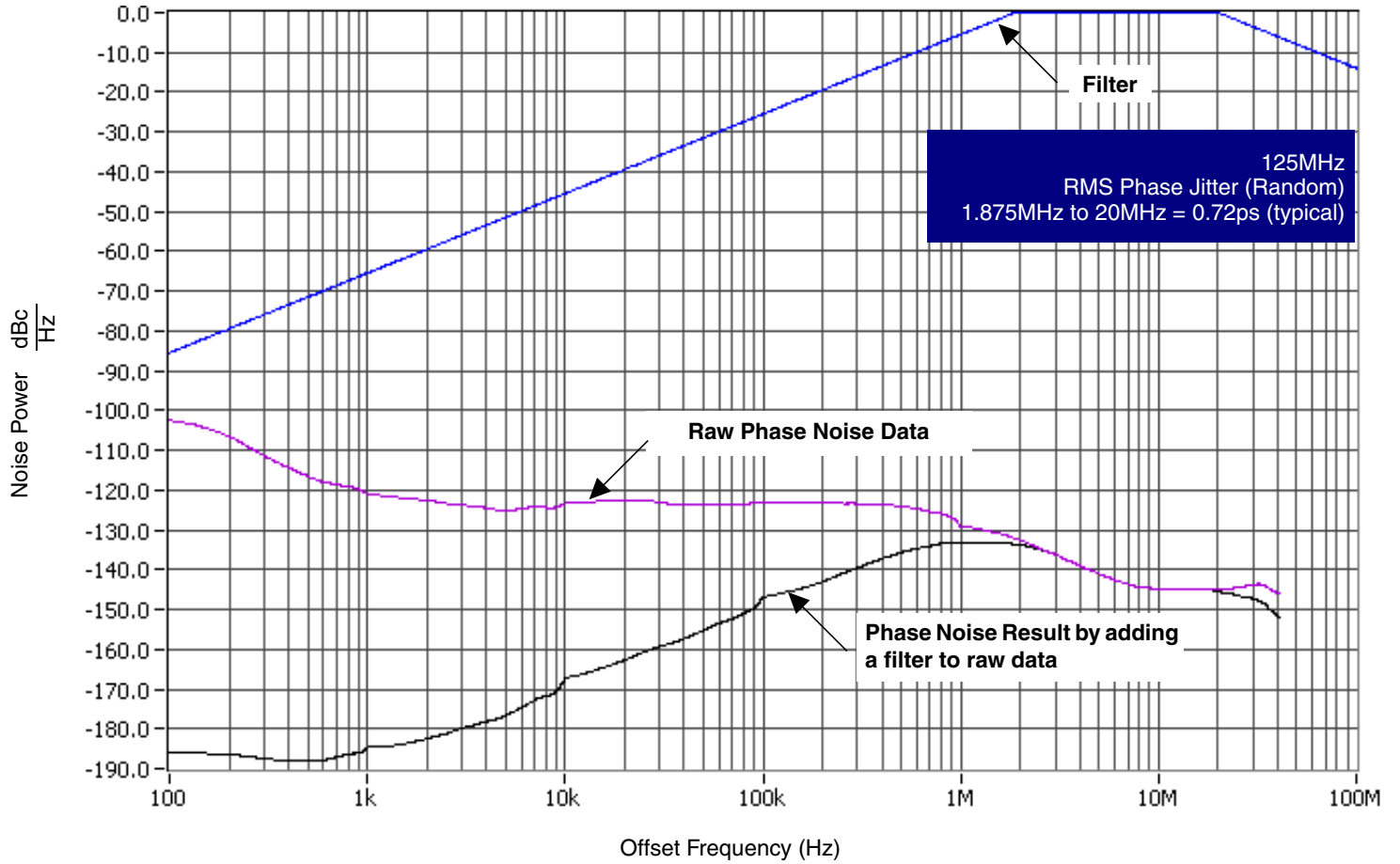
NOTE 1: Refer to the phase noise plot.

NOTE 2: Defined as skew within a bank of outputs at the same supply voltage and with equal load conditions.

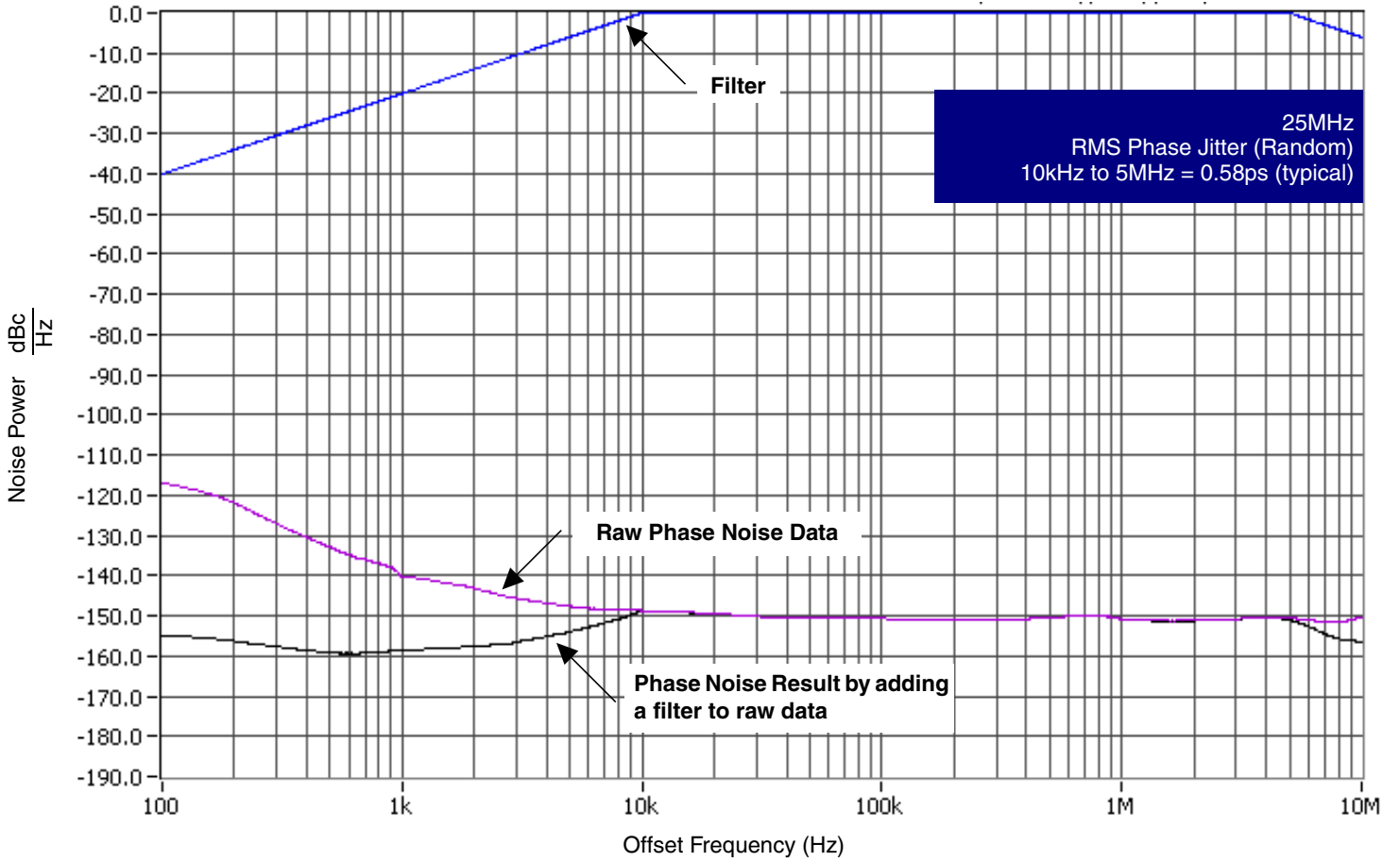
NOTE 3: Defined as skew between outputs on different devices operating at the same supply voltage, same frequency, same temperature and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at  $V_{DDO\_REF}/2$ .

NOTE 4: This parameter is defined in accordance with JEDEC Standard 65.

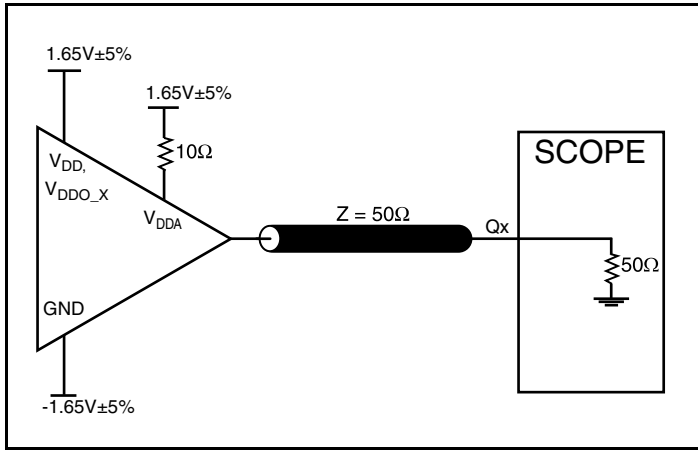
### Typical Phase Noise at 125MHz (QE output)



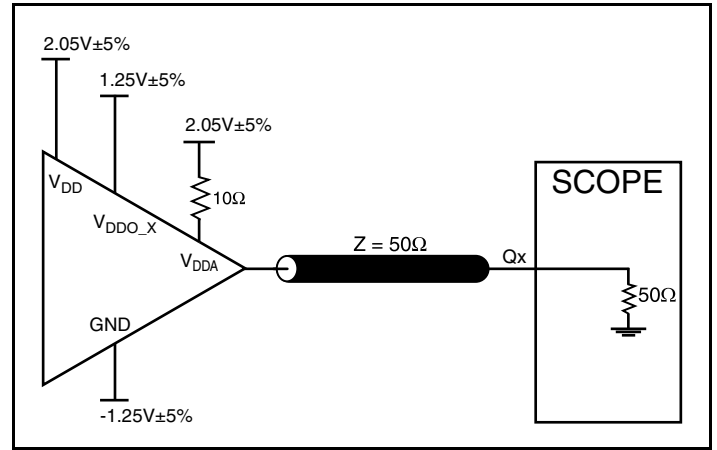
### Typical Phase Noise at 25MHz (QREF output)



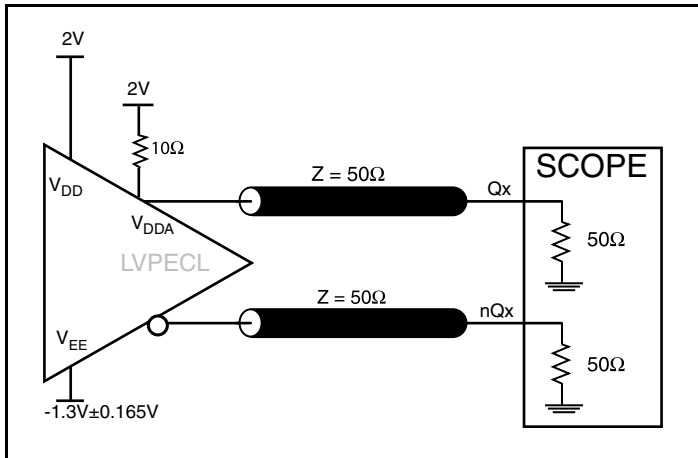
### Parameter Measurement Information



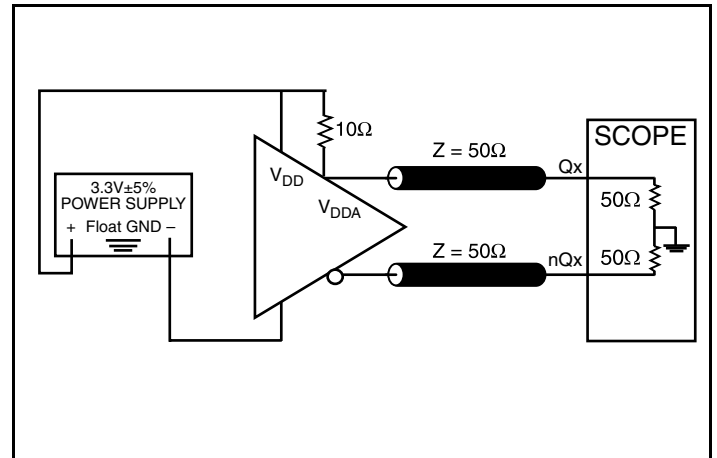
3.3V Core/3.3V LVCMOS Output Load AC Test Circuit



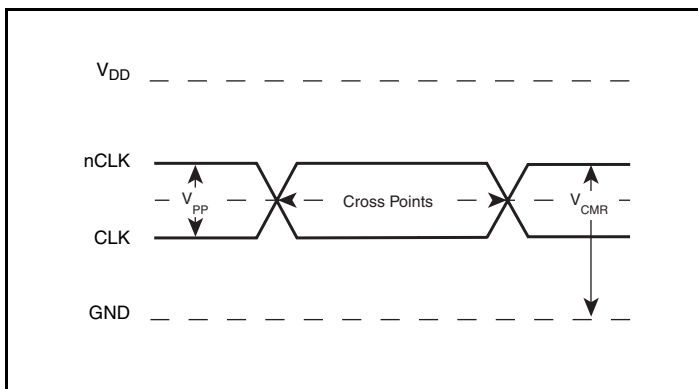
3.3V Core/2.5V LVCMOS Output Load AC Test Circuit



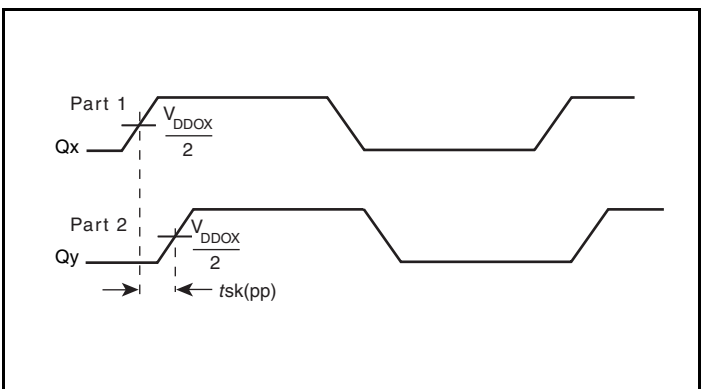
3.3V Core/3.3V LVPECL Output Load AC Test Circuit



3.3V Core/3.3V LVDS Output Load AC Test Circuit

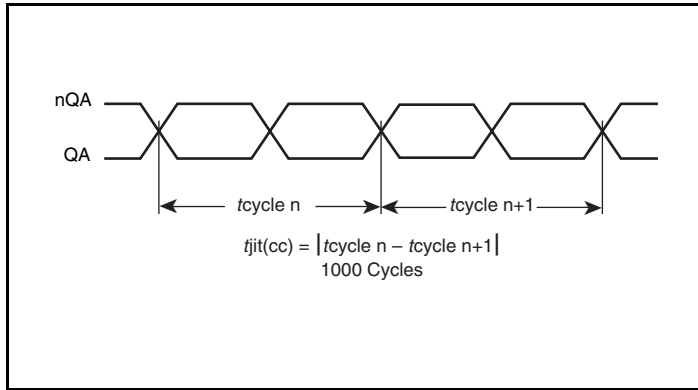


Differential Input Level

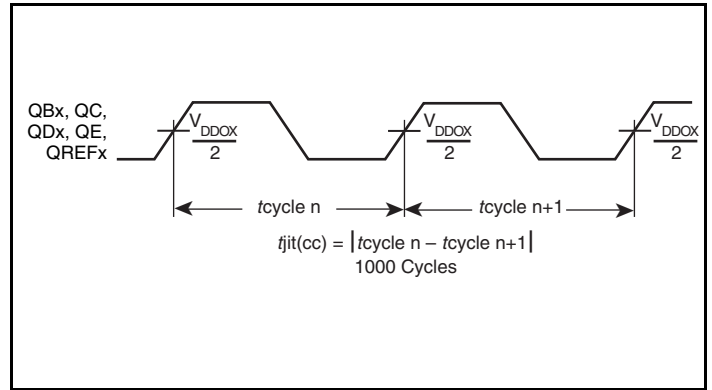


LVCMOS Part-to-Part Skew

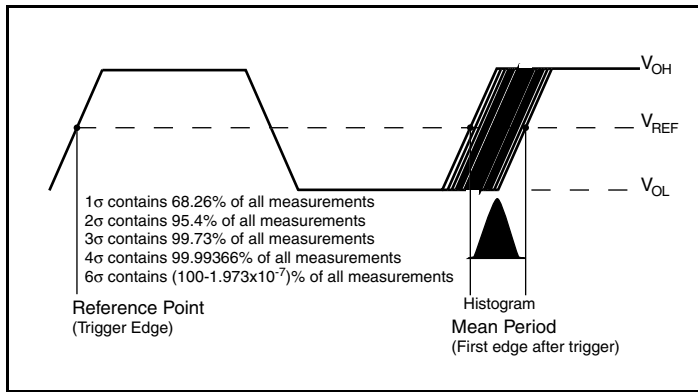
### Parameter Measurement Information, continued



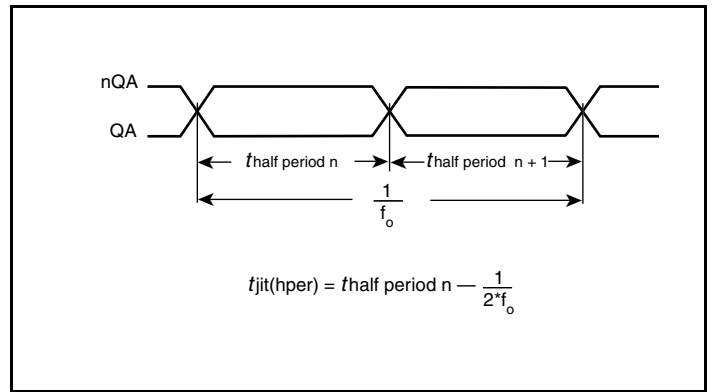
**Differential Cycle-to-Cycle Jitter**



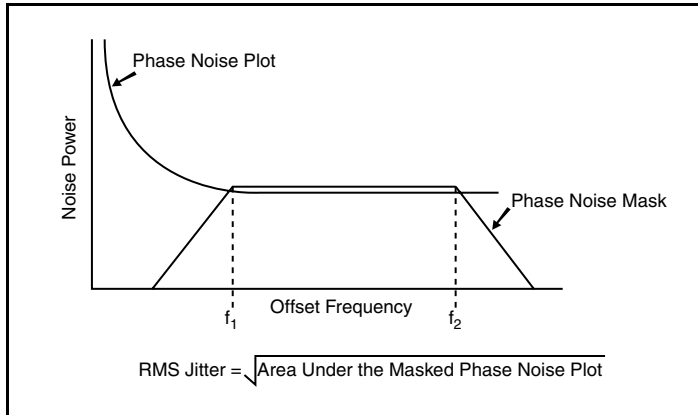
**LVCMOS Cycle-to-Cycle Jitter**



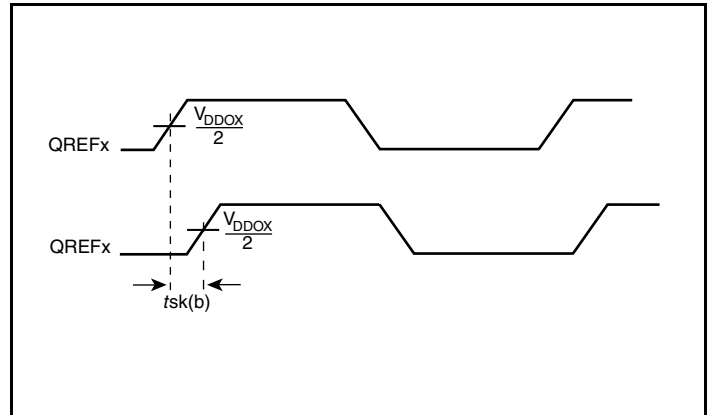
**Period Jitter**



**Half Period Jitter**

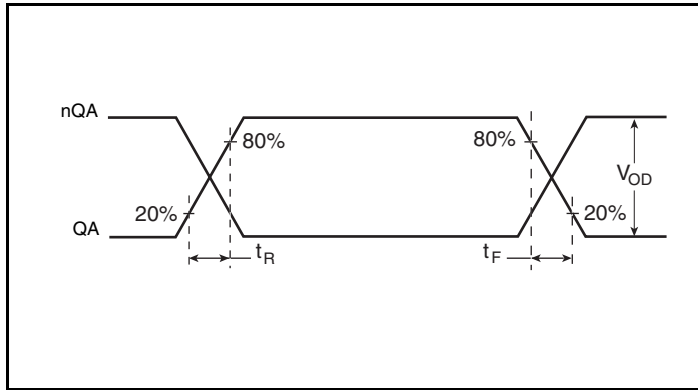


**RMS Phase Jitter**

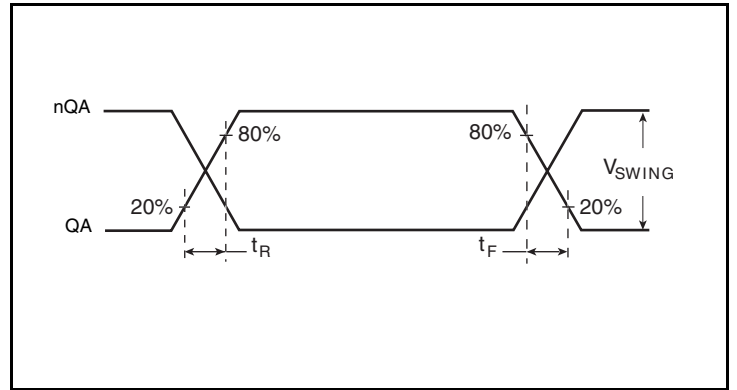


**LVCMOS Bank Skew (where X denotes QREF0 1, or 2)**

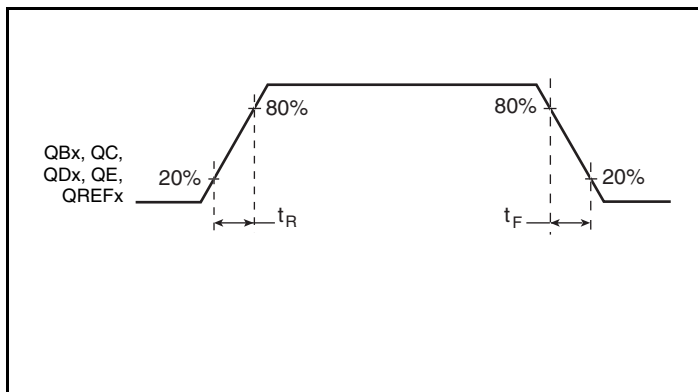
### Parameter Measurement Information, continued



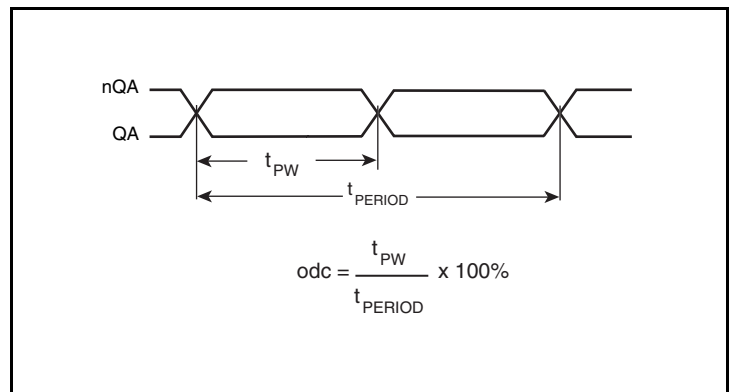
**LVDS Output Rise/Fall Time**



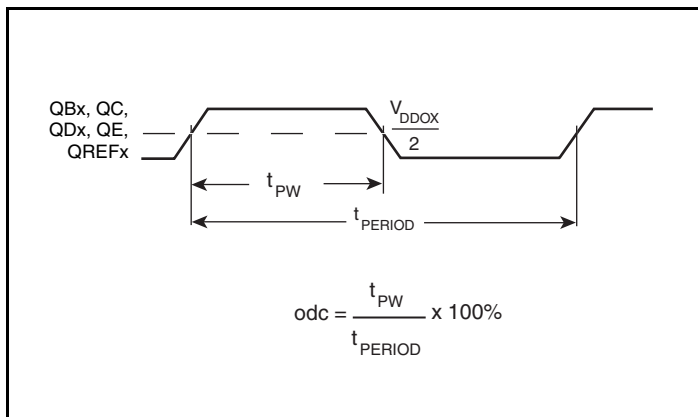
**LVPECL Output Rise/Fall Time**



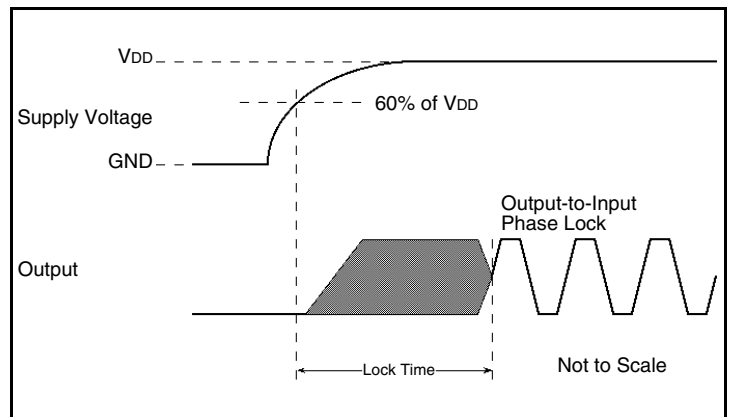
**LVCMOS Output Rise/Fall Time**



**Differential Output Duty Cycle/Pulse Width/Period**

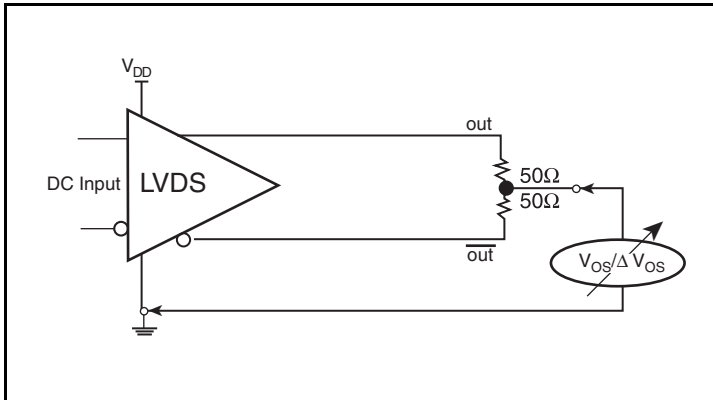


**LVCMOS Output Duty Cycle/Pulse Width/Period**

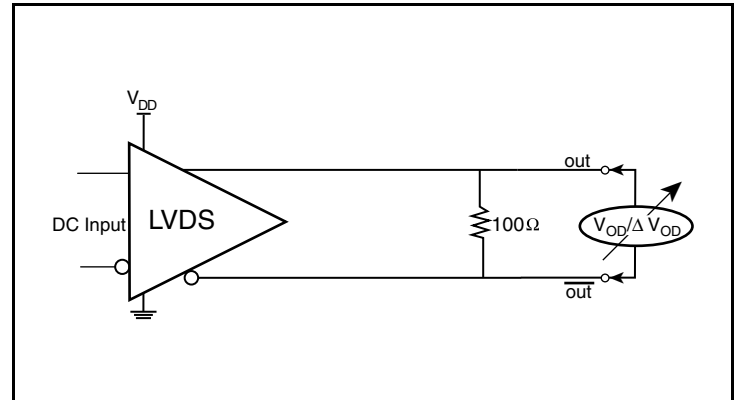


**Lock Time**

## Parameter Measurement Information, continued



**Offset Voltage Setup**



**Differential Output Voltage Setup**

## Applications Information

### Wiring the Differential Input to Accept Single-Ended Levels

Figure 1 shows how a differential input can be wired to accept single ended levels. The reference voltage  $V_{REF} = V_{CC}/2$  is generated by the bias resistors R1 and R2. The bypass capacitor (C1) is used to help filter noise on the DC bias. This bias circuit should be located as close to the input pin as possible. The ratio of R1 and R2 might need to be adjusted to position the  $V_{REF}$  in the center of the input voltage swing. For example, if the input clock swing is 2.5V and  $V_{CC} = 3.3V$ , R1 and R2 value should be adjusted to set  $V_{REF}$  at 1.25V. The values below are for when both the single ended swing and  $V_{CC}$  are at the same voltage. This configuration requires that the sum of the output impedance of the driver ( $R_o$ ) and the series resistance ( $R_s$ ) equals the transmission line impedance. In addition, matched termination at the input will attenuate the signal in half. This can be done in one of two ways. First, R3 and R4 in parallel should equal the transmission

line impedance. For most 50 $\Omega$  applications, R3 and R4 can be 100 $\Omega$ . The values of the resistors can be increased to reduce the loading for slower and weaker LVCMOS driver. When using single-ended signaling, the noise rejection benefits of differential signaling are reduced. Even though the differential input can handle full rail LVCMOS signaling, it is recommended that the amplitude be reduced. The datasheet specifies a lower differential amplitude, however this only applies to differential signals. For single-ended applications, the swing can be larger, however  $V_{IL}$  cannot be less than -0.3V and  $V_{IH}$  cannot be more than  $V_{CC} + 0.3V$ . Though some of the recommended components might not be used, the pads should be placed in the layout. They can be utilized for debugging purposes. The datasheet specifications are characterized and guaranteed by using a differential signal.

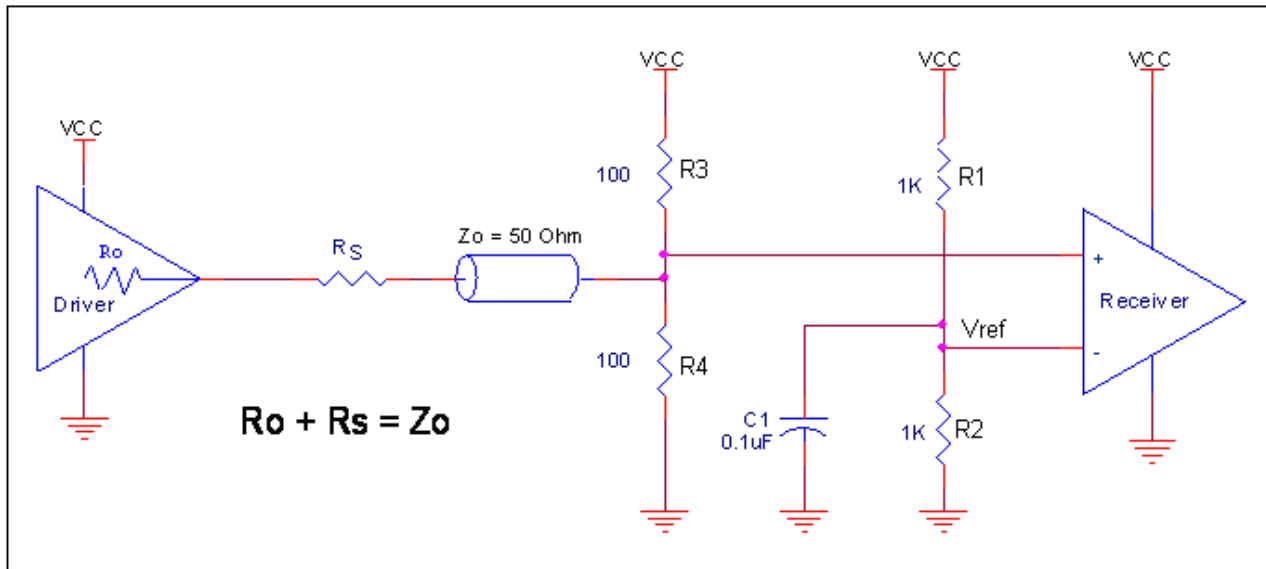
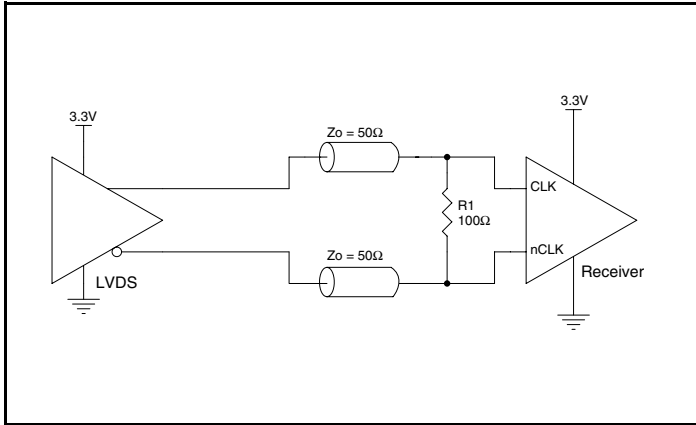


Figure 1. Recommended Schematic for Wiring a Differential Input to Accept Single-ended Levels

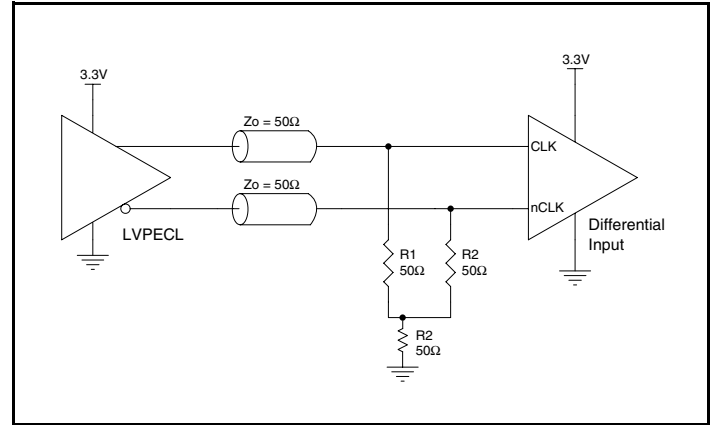
## Differential Clock Input Interface

The CLK /nCLK accepts LVDS, LVPECL, SSTL, and other differential signals. Both  $V_{\text{SWING}}$  and  $V_{\text{OH}}$  must meet the  $V_{\text{PP}}$  and  $V_{\text{CMR}}$  input requirements. *Figures 2A to 2D* show interface examples for the CLK/nCLK input driven by the most common driver types. The input

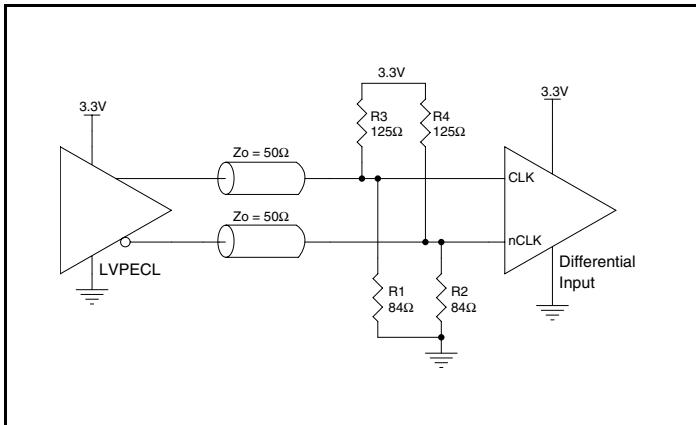
interfaces suggested here are examples only. Please consult with the vendor of the driver component to confirm the driver termination requirements. If the driver is from another vendor, use their termination recommendation.



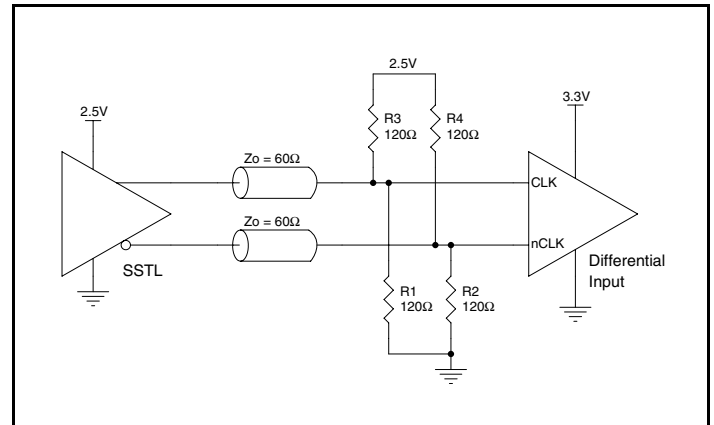
**Figure 2A. CLK/nCLK Input  
Driven by a 3.3V LVDS Driver**



**Figure 2B. CLK/nCLK Input  
Driven by a 3.3V LVPECL Driver**



**Figure 2C. CLK/nCLK Input  
Driven by a 3.3V LVPECL Driver**

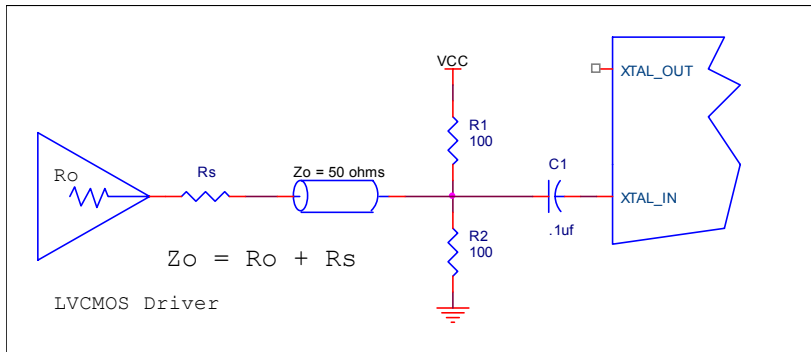


**Figure 2D. CLK/nCLK Input  
Driven by a 2.5V SSTL Driver**

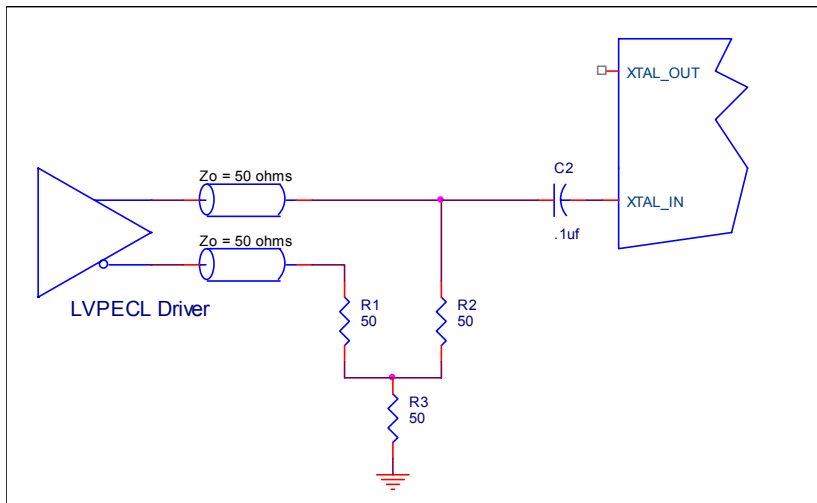
## Overdriving the XTAL Interface

The XTAL\_IN input can accept a single-ended LVCMOS signal through an AC coupling capacitor. A general interface diagram is shown in *Figure 3A*. The XTAL\_OUT pin can be left floating. The maximum amplitude of the input signal should not exceed 2V and the input edge rate can be as slow as 10ns. This configuration requires that the output impedance of the driver ( $R_o$ ) plus the series resistance ( $R_s$ ) equals the transmission line impedance. In addition,

matched termination at the crystal input will attenuate the signal in half. This can be done in one of two ways. First,  $R_1$  and  $R_2$  in parallel should equal the transmission line impedance. For most 50Ω applications,  $R_1$  and  $R_2$  can be 100Ω. This can also be accomplished by removing  $R_1$  and making  $R_2$  50Ω. By overdriving the crystal oscillator, the device will be functional, but note, the device performance is guaranteed by using a quartz crystal.



**Figure 3A. General Diagram for LVCMOS Driver to XTAL Input Interface**



**Figure 3B. General Diagram for LVPECL Driver to XTAL Input Interface**

## Termination for 3.3V LVPECL Outputs

The clock layout topology shown below is a typical termination for LVPECL outputs. The two different layouts mentioned are recommended only as guidelines.

The differential output pair is low impedance follower outputs that generate ECL/LVPECL compatible outputs. Therefore, terminating resistors (DC current path to ground) or current sources must be used for functionality. These outputs are designed to drive 50Ω

transmission lines. Matched impedance techniques should be used to maximize operating frequency and minimize signal distortion.

Figures 4A and 4B show two different layouts which are recommended only as guidelines. Other suitable clock layouts may exist and it would be recommended that the board designers simulate to guarantee compatibility across all printed circuit and clock component process variations.

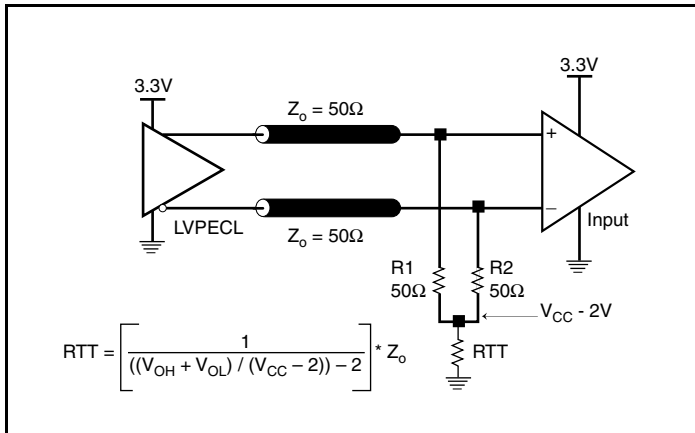


Figure 4A. 3.3V LVPECL Output Termination

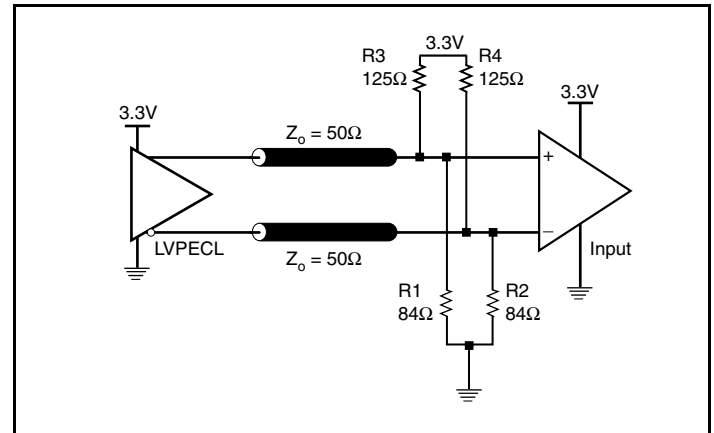


Figure 4B. 3.3V LVPECL Output Termination

## LVDS Driver Termination

A general LVDS interface is shown in Figure 5. Standard termination for LVDS type output structure requires both a 100Ω parallel resistor at the receiver and a 100Ω differential transmission line environment. In order to avoid any transmission line reflection issues, the 100Ω resistor must be placed as close to the receiver as possible. IDT offers a full line of LVDS compliant devices with two types of output structures: current source and voltage source. The standard

termination schematic as shown in Figure 5 can be used with either type of output structure. If using a non-standard termination, it is recommended to contact IDT and confirm if the output is a current source or a voltage source type structure. In addition, since these outputs are LVDS compatible, the amplitude and common mode input range of the input receivers should be verified for compatibility with the output.

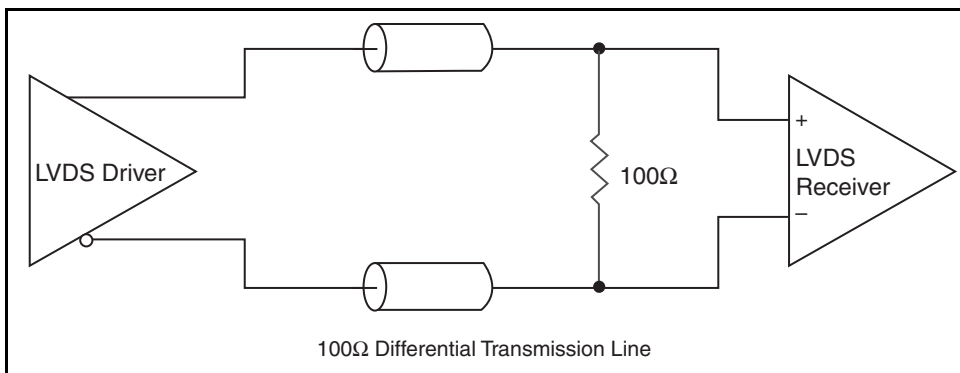


Figure 5. Typical LVDS Driver Termination

## EPAD Thermal Release Path

In order to maximize both the removal of heat from the package and the electrical performance, a land pattern must be incorporated on the Printed Circuit Board (PCB) within the footprint of the package corresponding to the exposed metal pad or exposed heat slug on the package, as shown in *Figure 6*. The solderable area on the PCB, as defined by the solder mask, should be at least the same size/shape as the exposed pad/slug area on the package to maximize the thermal/electrical performance. Sufficient clearance should be designed on the PCB between the outer edges of the land pattern and the inner edges of pad pattern for the leads to avoid any shorts.

While the land pattern on the PCB provides a means of heat transfer and electrical grounding from the package to the board through a solder joint, thermal vias are necessary to effectively conduct from the surface of the PCB to the ground plane(s). The land pattern must be connected to ground through these vias. The vias act as “heat pipes”. The number of vias (i.e. “heat pipes”) are application specific

and dependent upon the package power dissipation as well as electrical conductivity requirements. Thus, thermal and electrical analysis and/or testing are recommended to determine the minimum number needed. Maximum thermal and electrical performance is achieved when an array of vias is incorporated in the land pattern. It is recommended to use as many vias connected to ground as possible. It is also recommended that the via diameter should be 12 to 13mils (0.30 to 0.33mm) with 1oz copper via barrel plating. This is desirable to avoid any solder wicking inside the via during the soldering process which may result in voids in solder between the exposed pad/slug and the thermal land. Precautions should be taken to eliminate any solder voids between the exposed heat slug and the land pattern. Note: These recommendations are to be used as a guideline only. For further information, please refer to the Application Note on the Surface Mount Assembly of Amkor’s Thermally/Electrically Enhance Leadframe Base Package, Amkor Technology.

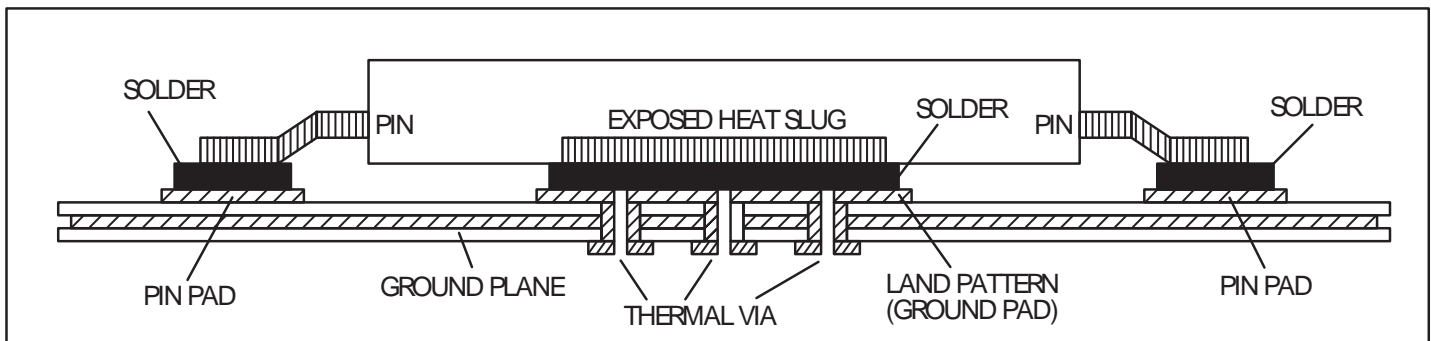


Figure 6. P.C. Assembly for Exposed Pad Thermal Release Path – Side View (drawing not to scale)

## Recommendations for Unused Input and Output Pins

### Inputs:

#### CLK/nCLK Inputs

For applications not requiring the use of the differential input, both CLK and nCLK can be left floating. Though not required, but for additional protection, a 1k $\Omega$  resistor can be tied from CLK to ground.

#### Crystal Inputs

For applications not requiring the use of the crystal oscillator input, both XTAL\_IN and XTAL\_OUT can be left floating. Though not required, but for additional protection, a 1k $\Omega$  resistor can be tied from XTAL\_IN to ground.

#### LVC MOS Control Pins

All control pins have internal pulldowns; additional resistance is not required but can be added for additional protection. A 1k $\Omega$  resistor can be used.

### Outputs:

#### LVPECL Outputs

All unused LVPECL outputs can be left floating. We recommend that there is no trace attached. Both sides of the differential output pair should either be left floating or terminated.

#### LVDS Outputs

All unused LVDS output pairs can be either left floating or terminated with 100 $\Omega$  across. If they are left floating, there should be no trace attached.

#### LVC MOS Outputs

All unused LVC MOS output can be left floating. There should be no trace attached.

### Schematic Example

Figure 7 shows an example of ICS8430S10I-02 application schematic. In this example, the device is operated at  $V_{DD} = V_{DDO\_B} = V_{DDO\_CD} = V_{DDO\_E} = V_{DDO\_REF} = 3.3V$ . An 18pF parallel resonant 25MHz crystal is used. The load capacitance  $C1 = 18pF$  and  $C2 = 18pF$  are recommended for frequency accuracy. Depending on the parasitics of the printed circuit board layout, these values might require a slight adjustment to optimize the frequency accuracy. Crystals with other load capacitance specifications can be used. This will require adjusting  $C1$  and  $C2$ . For this device, the crystal load capacitors are required for proper operation.

As with any high speed analog circuitry, the power supply pins are vulnerable to noise. To achieve optimum jitter performance, power supply isolation is required. The ICS8430S10I-02 provides separate power supplies to isolate from coupling into the internal PLL.

In order to achieve the best possible filtering, it is recommended that the placement of the filter components be on the device side of the

PCB as close to the power pins as possible. If space is limited, the 0.1uF capacitor in each power pin filter should be placed on the device side of the PCB and the other components can be placed on the opposite side.

Power supply filter recommendations are a general guideline to be used for reducing external noise from coupling into the devices. This low-pass filter starts to attenuate noise at approximately 10kHz. If a specific frequency noise component is known, such as switching power supply frequencies, it is recommended that component values be adjusted and if required, additional filtering be added. Additionally, good general design practices for power plane voltage stability suggests adding bulk capacitances in the local area of all devices.

The schematic example focuses on functional connections and is not configuration specific. Refer to the pin description and functional tables in the datasheet to ensure the logic control inputs are properly set.

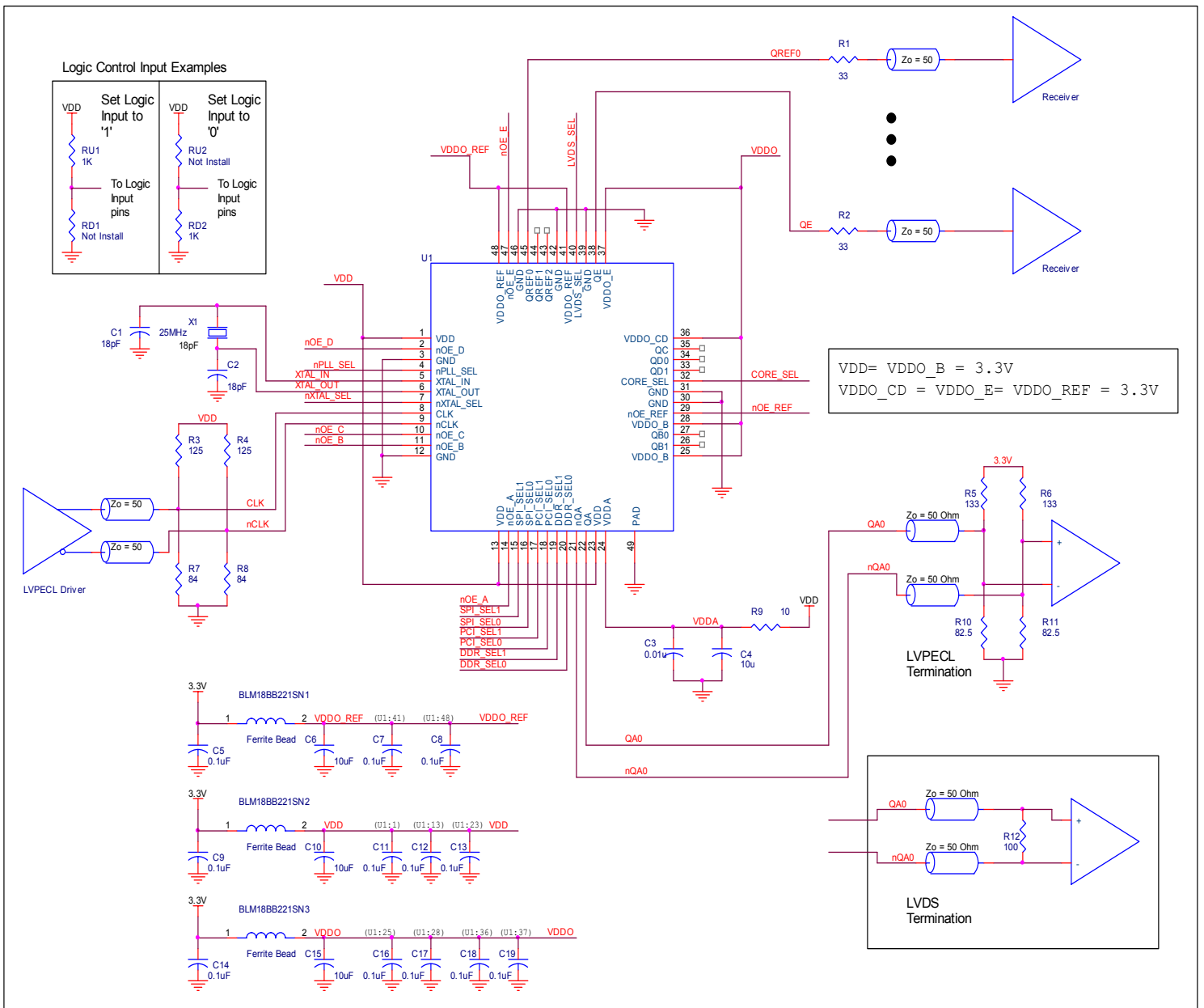


Figure 7. ICS8430S10I-02 Layout Example

## Power Considerations (LVCMOS/LVDS Outputs)

This section provides information on power dissipation and junction temperature for the ICS8430S10I-02. Equations and example calculations are also provided.

### 1. Power Dissipation.

The total power dissipation for the ICS8430S10I-02 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for  $V_{DD} = 3.3V + 5\% = 3.465V$ , which gives worst case results.

#### Core and LVDS Output Power Dissipation

- Power (core, LVDS) =  $V_{DD\_MAX} * (I_{DD} + I_{DDA}) = 3.465V * (192mA + 25mA) = \mathbf{751.9mW}$

#### LVCMOS Output Power Dissipation

- Output Impedance  $R_{OUT}$  Power Dissipation due to Loading  $50\Omega$  to  $V_{DDO}/2$   
Output Current  $I_{OUT} = V_{DDO\_MAX} / [2 * (50\Omega + R_{OUT})] = 3.465V / [2 * (50\Omega + 20\Omega)] = \mathbf{24.80mA}$
- Power Dissipation on the  $R_{OUT}$  per LVCMOS output  
Power ( $R_{OUT}$ ) =  $R_{OUT} * (I_{OUT})^2 = 20\Omega * (24.80mA)^2 = \mathbf{12.3mW}$  per output
- Total Power Dissipation on the  $R_{OUT}$   
**Total Power ( $R_{OUT}$ ) =  $12.3mW * 9 = \mathbf{110.7mW}$**
- Dynamic Power Dissipation at 133MHz  
Power (133MHz) =  $C_{PD} * Frequency * (V_{DDO})^2 = 10pF * 133MHz * (3.465V)^2 = \mathbf{16mW}$  per output  
**Total Power (133MHz) =  $16mW * 6 = \mathbf{96mW}$**
- Dynamic Power Dissipation at 25MHz  
Power (25MHz) =  $C_{PD} * Frequency * (V_{DDO})^2 = 10pF * 25MHz * (3.465V)^2 = \mathbf{3mW}$  per output  
**Total Power (25MHz) =  $3mW * 3 = \mathbf{9mW}$**

#### Total Power Dissipation

- Total Power**  
= Power (core, LVDS) + Total Power ( $R_{OUT}$ ) + Total Power (133MHz) + Total Power (25MHz)  
=  $751.9mW + 110.7mW + 96mW + 9mW$   
= **967.6mW**

## 2. Junction Temperature.

Junction temperature,  $T_j$ , is the temperature at the junction of the bond wire and bond pad directly affects the reliability of the device. The maximum recommended junction temperature is 125°C. Limiting the internal transistor junction temperature,  $T_j$ , to 125°C ensures that the bond wire and bond pad temperature remains below 125°C.

The equation for  $T_j$  is as follows:  $T_j = \theta_{JA} * Pd\_total + T_A$

$T_j$  = Junction Temperature

$\theta_{JA}$  = Junction-to-Ambient Thermal Resistance

$Pd\_total$  = Total Device Power Dissipation (example calculation is in section 1 above)

$T_A$  = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 33.1°C/W per Table 7A below.

Therefore,  $T_j$  for an ambient temperature of 85°C with all outputs switching is:

$$85^\circ\text{C} + 0.968\text{W} * 33.1^\circ\text{C/W} = 117^\circ\text{C}. \text{ This is below the limit of } 125^\circ\text{C}.$$

This calculation is only an example.  $T_j$  will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (multi-layer).

**Table 7A. Thermal Resistance  $\theta_{JA}$  for 48 Lead TQFP, EPAD Forced Convection**

$\theta_{JA}$ Vs. Air Flow			
Meters per Second	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	33.1°C/W	27.2°C/W	25.7°C/W

## Power Considerations (LVCMOS/LVPECL Outputs)

This section provides information on power dissipation and junction temperature for the ICS8430S10I-02. Equations and example calculations are also provided.

### 1. Power Dissipation.

The total power dissipation for the ICS8430S10I-02 is the sum of the core power plus the analog power plus the power dissipated in the load(s). The following is the power dissipation for  $V_{DD} = 3.3V + 5\% = 3.465V$ , which gives worst case results.

#### Core and LVPECL Output Power Dissipation

- Power (core)<sub>MAX</sub> =  $V_{DD\_MAX} * I_{EE\_MAX} = 3.465V * 180mA = \mathbf{623.7mW}$
- Power (output)<sub>MAX</sub> = **30mW/Loaded Output Pair**

#### LVCMOS Output Power Dissipation

- Output Impedance  $R_{OUT}$  Power Dissipation due to Loading  $50\Omega$  to  $V_{DDO}/2$   
Output Current  $I_{OUT} = V_{DDO\_MAX} / [2 * (50\Omega + R_{OUT})] = 3.465V / [2 * (50\Omega + 20\Omega)] = \mathbf{24.80mA}$
- Power Dissipation on the  $R_{OUT}$  per LVCMOS output  
Power ( $R_{OUT}$ ) =  $R_{OUT} * (I_{OUT})^2 = 20\Omega * (24.80mA)^2 = \mathbf{12.3mW}$  per output
- Total Power Dissipation on the  $R_{OUT}$   
**Total Power ( $R_{OUT}$ ) =  $12.3mW * 9 = \mathbf{110.7mW}$**
- Dynamic Power Dissipation at 133MHz  
Power (133MHz) =  $C_{PD} * Frequency * (V_{DDO})^2 = 10pF * 133MHz * (3.465V)^2 = \mathbf{16mW}$  per output  
**Total Power (133MHz) =  $16mW * 6 = \mathbf{96mW}$**
- Dynamic Power Dissipation at 25MHz  
Power (25MHz) =  $C_{PD} * Frequency * (V_{DDO})^2 = 10pF * 25MHz * (3.465)^2 = \mathbf{3mW}$  per output  
**Total Power (25MHz) =  $3mW * 3 = \mathbf{9mW}$**

#### Total Power Dissipation

- **Total Power**  
= Power (core) + Power (LVPECL output) + Total Power ( $R_{OUT}$ ) + Total Power (133MHz) + Total Power (25MHz)  
=  $623.7mW + 30mW + 110.7mW + 96mW + 9mW$   
= **869.4mW**

## 2. Junction Temperature.

Junction temperature,  $T_j$ , is the temperature at the junction of the bond wire and bond pad directly affects the reliability of the device. The maximum recommended junction temperature is 125°C. Limiting the internal transistor junction temperature,  $T_j$ , to 125°C ensures that the bond wire and bond pad temperature remains below 125°C.

The equation for  $T_j$  is as follows:  $T_j = \theta_{JA} * Pd\_total + T_A$

$T_j$  = Junction Temperature

$\theta_{JA}$  = Junction-to-Ambient Thermal Resistance

$Pd\_total$  = Total Device Power Dissipation (example calculation is in section 1 above)

$T_A$  = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 33.1°C/W per Table 7B below.

Therefore,  $T_j$  for an ambient temperature of 85°C with all outputs switching is:

$$85^\circ\text{C} + 0.869\text{W} * 33.1^\circ\text{C}/\text{W} = 113.8^\circ\text{C}. \text{ This is below the limit of } 125^\circ\text{C}.$$

This calculation is only an example.  $T_j$  will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (multi-layer).

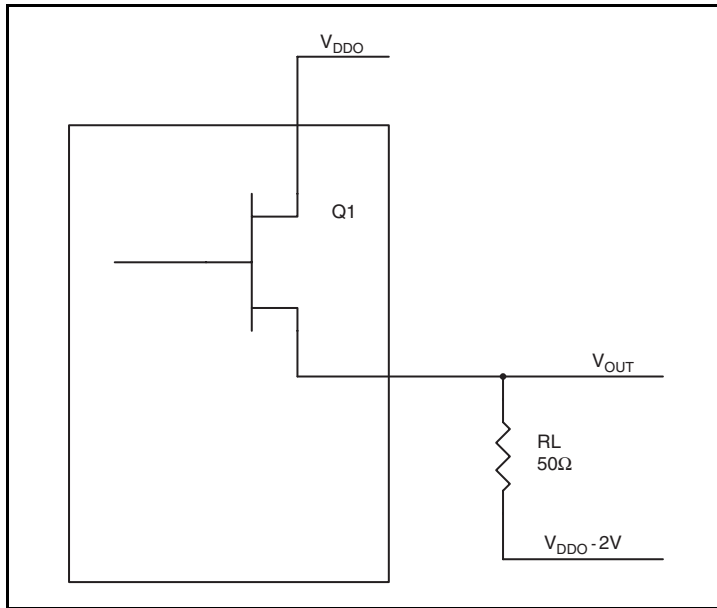
**Table 7B. Thermal Resistance  $\theta_{JA}$  for 48 Lead TQFP, EPAD Forced Convection**

$\theta_{JA}$ Vs. Air Flow			
Meters per Second	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	33.1°C/W	27.2°C/W	25.7°C/W

### 3. Calculations and Equations.

The purpose of this section is to calculate the power dissipation for the LVPECL output pairs.

The LVPECL output driver circuit and termination are shown in *Figure 8*.



**Figure 8. LVPECL Driver Circuit and Termination**

To calculate worst case power dissipation into the load, use the following equations which assume a  $50\Omega$  load, and a termination voltage of  $V_{DDO} - 2V$ .

- For logic high,  $V_{OUT} = V_{OH\_MAX} = V_{DDO\_MAX} - 0.9V$   
( $V_{DDO\_MAX} - V_{OH\_MAX}$ ) = **0.9V**
- For logic low,  $V_{OUT} = V_{OL\_MAX} = V_{DDO\_MAX} - 1.7V$   
( $V_{DDO\_MAX} - V_{OL\_MAX}$ ) = **1.7V**

$Pd\_H$  is power dissipation when the output drives high.

$Pd\_L$  is the power dissipation when the output drives low.

$$Pd\_H = [(V_{OH\_MAX} - (V_{DDO\_MAX} - 2V))/R_L] * (V_{DDO\_MAX} - V_{OH\_MAX}) = [(2V - (V_{DDO\_MAX} - V_{OH\_MAX}))/R_L] * (V_{DDO\_MAX} - V_{OH\_MAX}) = [(2V - 0.9V)/50\Omega] * 0.9V = \mathbf{19.8mW}$$

$$Pd\_L = [(V_{OL\_MAX} - (V_{DDO\_MAX} - 2V))/R_L] * (V_{DDO\_MAX} - V_{OL\_MAX}) = [(2V - (V_{DDO\_MAX} - V_{OL\_MAX}))/R_L] * (V_{DDO\_MAX} - V_{OL\_MAX}) = [(2V - 1.7V)/50\Omega] * 1.7V = \mathbf{10.2mW}$$

Total Power Dissipation per output pair =  $Pd\_H + Pd\_L = \mathbf{30mW}$

## Reliability Information

**Table 8.  $\theta_{JA}$  vs. Air Flow Table for a 48 Lead TQFP, EPAD**

$\theta_{JA}$ vs. Air Flow			
Meters per Second	<b>0</b>	<b>1</b>	<b>2.5</b>
Multi-Layer PCB, JEDEC Standard Test Boards	33.1°C/W	27.2°C/W	25.7°C/W

## Transistor Count

The transistor count for ICS8430S10I-02 is: 10,871

## Package Outline and Package Dimensions

### Package Outline - Y Suffix for 48 Lead TQFP, EPAD

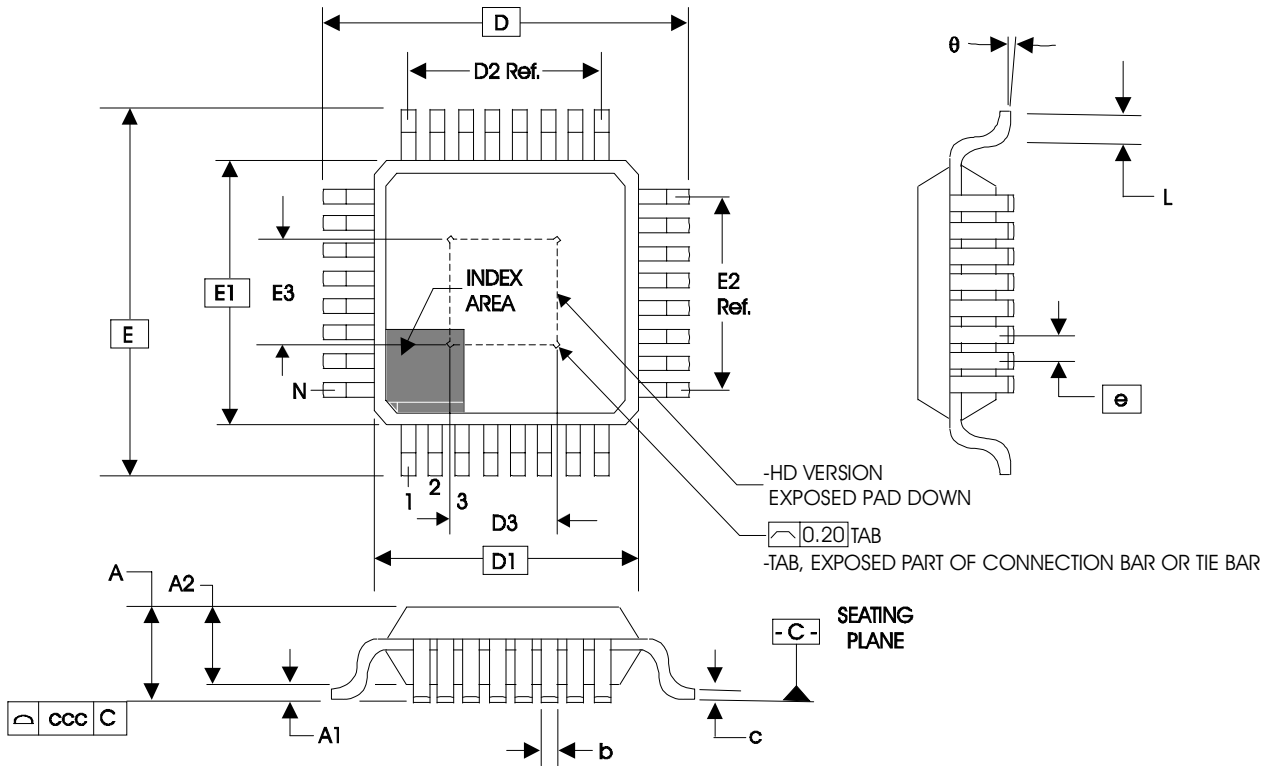


Table 9. Package Dimensions 48L TQFP, EPAD

JEDEC Variation: ABC - HD			
All Dimensions in Millimeters			
Symbol	Minimum	Nominal	Maximum
N		48	
A			1.20
A1	0.05	0.10	0.15
A2	0.95	1.00	1.05
b	0.17	0.22	0.27
c	0.09		0.20
D & E		9.00 Basic	
D1 & E1		7.00 Basic	
D2 & E2		5.50 Ref.	
D3 & E3		3.5	
e		0.5 Basic	
L	0.45	0.60	0.75
$\theta$	0°		7°
ccc			0.08

Reference Document: JEDEC Publication 95, MS-026

## Ordering Information

**Table 10. Ordering Information**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
8430S10BYI-02LF	ICS0S10BI02L	"Lead-Free" 48 TQFP, EPAD	Tray	-40°C to 85°C
8430S10BYI-02LFT	ICS0S10BI02L	"Lead-Free" 48 TQFP, EPAD	1000 Tape & Reel	-40°C to 85°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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## Revision History Sheet

Rev	Table	Page	Description of Change	Date
B	T6	9 15	AC Characteristics Table - added Lock Time parameter. Added Lock Time measurement drawing.	11/2/09
C	T4F          T9	1 2 8 16 17 18 19 21 28	Features section - corrected Differential Input bullet (deleted HCSL and LVHSTL levels). Block Diagram - corrected naming convention for SPI4_SEL1:0 to SPI_SEL1:0. Differential DC Characteristics Table - corrected VCMR levels from 0.5V min / $V_{DD}$ - 0.85V max to 1.2V min / $V_{DD}$ max. Deleted <i>Power Supply Filtering Technique</i> application note (see Schematic Example). Updated <i>Wiring the Differential Input to Accept Single-ended Levels</i> application note. Corrected <i>Differential Clock Input Interface</i> application note (deleted HCSL and LVHSTL levels). Deleted <i>Crystal Input Interface</i> application note (see Schematic Example). Updated <i>Overdriving the XTAL Interface</i> application note. Updated <i>LVDS Driver Termination</i> application note. Updated <i>Schematic Example</i> application note and diagram. Corrected D3/E3 dimensions. Updated Package Outline.	1/17/11

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